Alternative Setup for Long-Duration Low-Duty-Cycle 600 °C **Ambient Testing of SiC Integrated** Circuits

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Agenda



Introduction

- Solution Setup Overview
 - -Compact Oven Overview
 - -Testing Setup Overview

Oven Enclosure Design and Testing

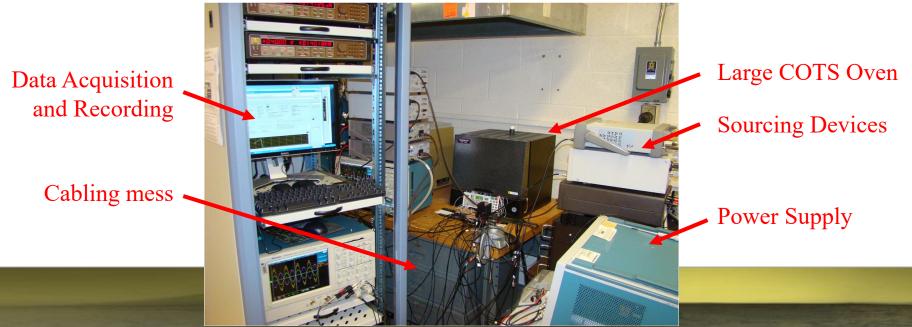
- -Mechanical Construction
- -Thermal Characterization
- -Oven Controller
- Measuring ICs in the Oven
- Conclusion



Introduction – The Problem



- On the surface of Venus, the average temperature is 460°C
 - -Requires specialized high temperature electronics (SiC)
 - -Commercial off the shelf (COTS) ovens are physically large
 - -Each SiC IC testing requires unique wiring and measuring



Solution – Compact Oven Overview



 Team designed and created a smaller oven that can be connected nicely with a NI PXI system



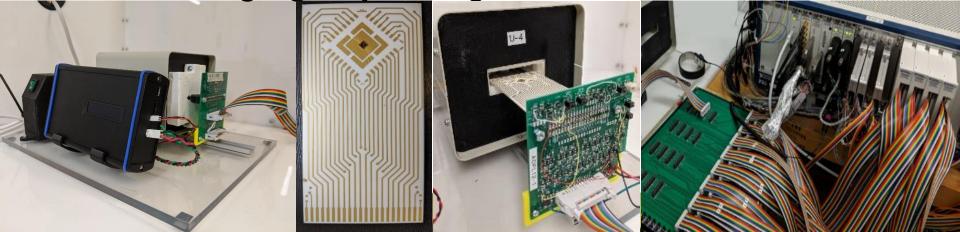
Old COTS Oven vs New Compact Oven

New Compact Oven Footprint

Solution – Testing Setup Overview



- Oven substrate board: houses the DUT, mounts to the fixture board, and slides into the oven
- Fixture board: reroutes the DUT connections to signals and power pins for the NI PXI system
- Breakout board: provides a way to test 32 ovens without changing any wiring



New Compact Oven

Oven substrate board

Fixture board

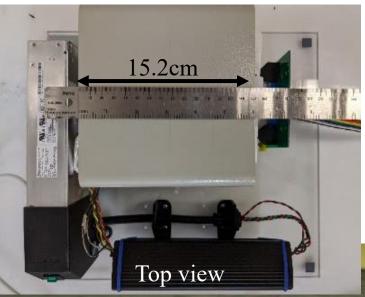
Breakout board to ovens and PXI matrix measurement unit

Oven – Mechanical Construction

TMAPS NASA

- Compact COTS empty metal box
 - -15.2 x 15.2 x 12.7 cm
- Oven electronics are physically separated
- Within frame
 - Custom ceramic heater cavity assembly
 - 2 types of high temperature insulation
 - Hard 1 1/2 inch thick
 - Soft ½ inch thick





Oven – Mechanical Construction Cont.

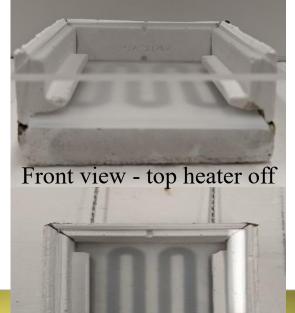
MAPS NASA

- Custom ceramic heater cavity is Silicon Oxide based
- The Custom ceramic heater cavity assembly contains:
 - -Custom ceramic heater cavity
 - -2 COTS quartz plates
 - Either polished or unpolished
 - 2 COTS high temperature heating coils



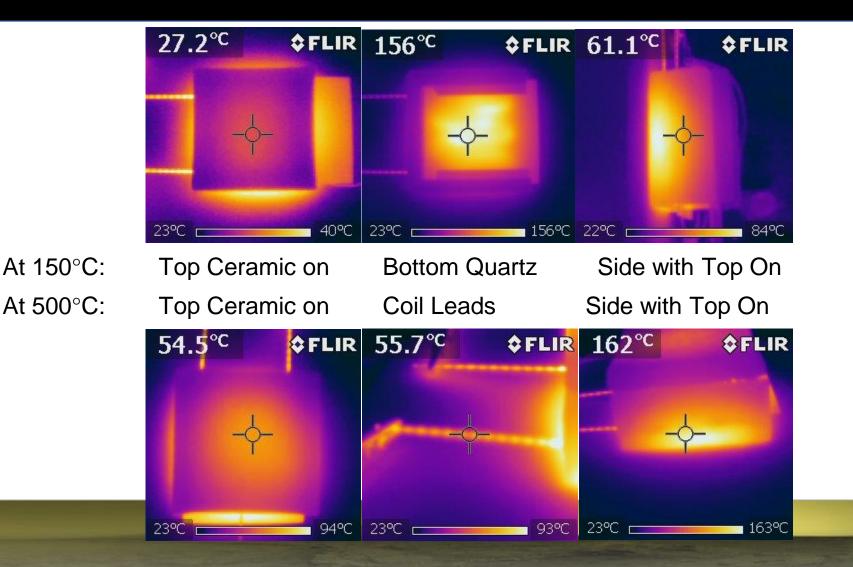


Front view - full assembly



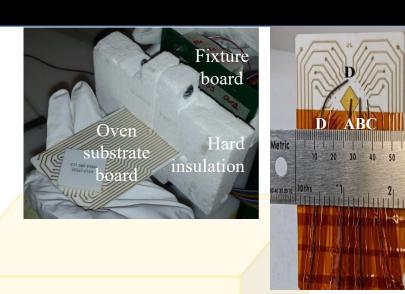
Oven – Thermal Characterization





Oven – Thermal Characterization Cont.

- Oven tested up to 600°C
- Few findings for low error:
 - Oven substrate board needs
 to be pushed all the way in
 - Use the hard high temperature insulation to close off the front of the oven
 - -Be mindful of the ramp rate
 - Oven heating configuration provides different levels of power.



~4600

~17.5C

~17.5C

~30

TC C

TC B

TC A

TC D

10

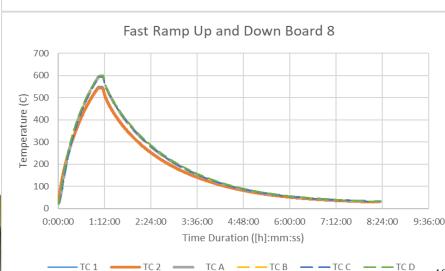
Oven – Thermal Characterization Cont.

- •<5 °C variance with oven substrate board pushed fully in
 - isolating both top and bottom heater
- •TC1 and TC2 see less heat than the substrate
- Oven heat was unable to keep up with the ramp rate for the fast ramp up



700 600 9 500 Temperature 400 300 200 100 0:00:00 4:48:00 9:36:00 14:24:00 19:12:00 24:00:00 28:48:00 Time Duration ([h]:mm:ss)

Slow Ramp Up, Fast Ramp Down Board 8

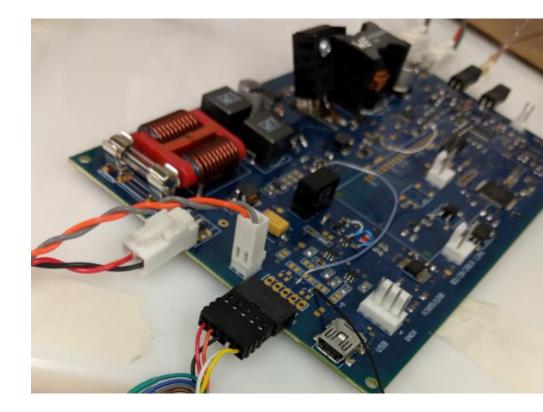


-- TC 2 - TC A - TC B - TC C - TC D



Oven – Controller

- Basic characteristics:
 - -DC powered
 - -Programmable
 - -Separates the power between:
 - Control
 - Oven heating
 - Able to network ovens together



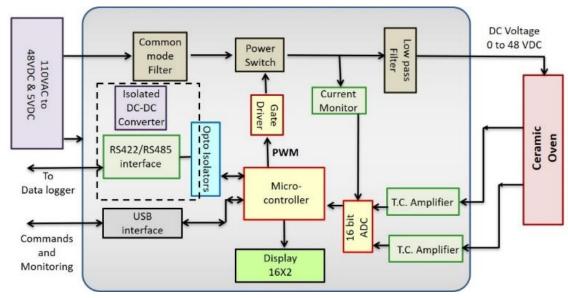




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Oven – Controller Cont.

- Details of the controller:
 - -Controls oven target temperature and oven ramp rate independently
 - -Supplies up to 400 Watts
 - 120 Watts typical
 - –48V line to heat ovens
 - -5V line for control

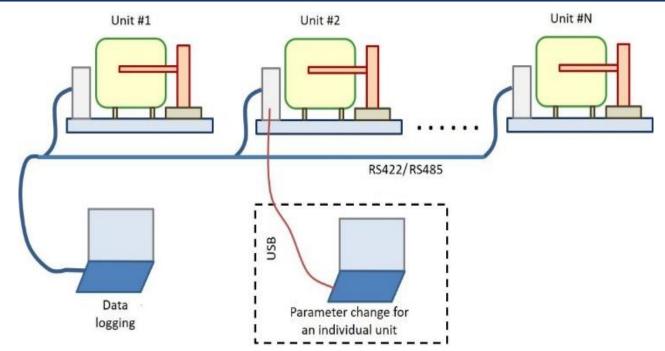


Block diagram of oven controller



Oven – Controller Cont.



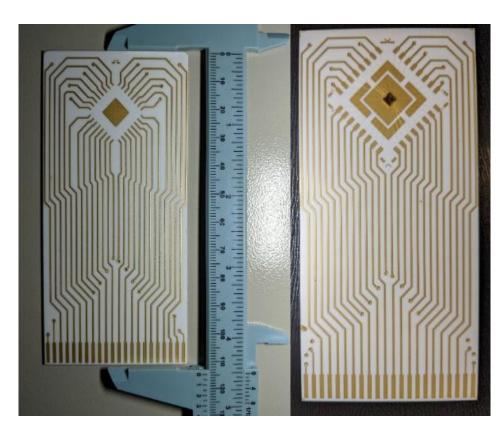


Using a second communication port, the ovens can be networked together and controlled by typing in the oven's specific identification number.

Measuring ICs in the Ovens

TMAPS NASA

- Ceramic package resides on a movable 11.43 cm long Al₂O₃ substrate.
- Able to connect package via wire bonding
- Substrate dissipates the heat enough to connect to a room temperature connector
- This board connects to a NI PXI system for unique IC testing

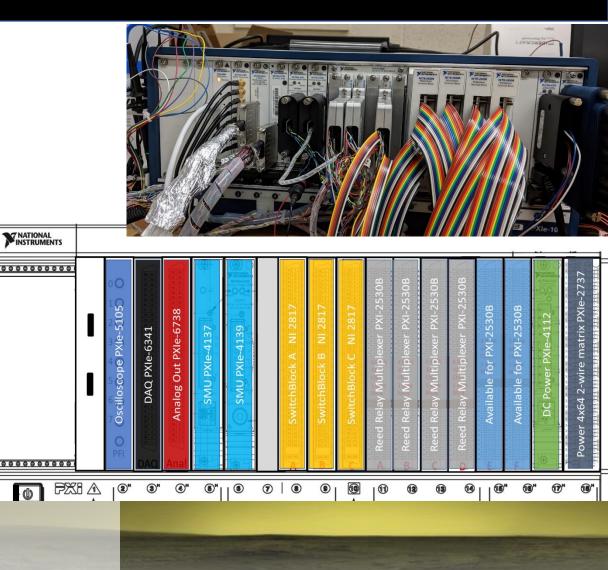




Measuring ICs in the Ovens Cont.



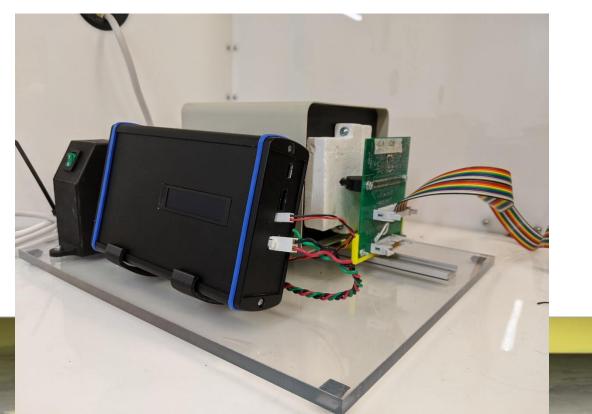
- PXI system details
- Switching
 - -Reed Relays
 - -NI SwitchBlock
- Measuring
 - -Oscilloscopes
 - –Analog Inputs
 - -SMU
- Sourcing
 - -SMU
 - -DC Power
 - -Analog Outputs







- Achieved a smaller footprint of high temperature ovens
- Achieved a scalable testing rig
- Ceramic heating block can reach up to 600C



Questions?

